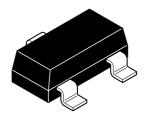


ZXMN2B01F

20V SOT23 N-channel enhancement mode MOSFET with low gate drive capability

Summary

V _{(BR)DSS}	$R_{DS(on)}$ (Ω)	I _D (A)	
20	0.100 @ V _{GS} = 4.5V	2.4	
	0.150 @ V _{GS} = 2.5V	2.0	
	0.200 @ V _{GS} = 1.8V	1.7	



Description

This new generation trench MOSFET from Zetex features low on-resistance achievable with low gate drive.

Features

- · Low on-resistance
- · Fast switching speed
- · Low gate drive capability
- SOT23 package

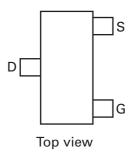
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Applications

- DC-DC converters
- · Power management functions
- · Disconnect switches
- Motor control

Ordering information

Device	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMN2B01FTA	7	8	3,000



Device marking

2B1

Absolute maximum ratings

Parameter	Symbol	Limit	Unit	
Drain-source voltage	V _{DSS}	20	V	
Gate-source voltage		V _{GS}	±8	V
Continuous drain current	@ V _{GS} = 4.5V; T _{amb} =25°C ^(b)	I _D	2.4	Α
	@ V _{GS} = 4.5V; T _{amb} =70°C ^(b)		1.9	Α
	@ V _{GS} = 4.5V; T _{amb} =25°C ^(a)		2.1	Α
Pulsed drain current ^(c)	I _{DM}	11.8	Α	
Continuous source current	I _S	1.4	Α	
Pulsed source current (boo	I _{SM}	11.8	Α	
Power dissipation at T _{amb} :	P _D	625	mW	
Linear derating factor		5	mW/°C	
Power dissipation at T _{amb}	P _D	806	mW	
Linear derating factor		6.4	mW/°C	
Operating and storage tem	T _j , T _{stg}	-55 to +150	°C	

Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient ^(a)	$R_{\Theta JA}$	200	°C/W
Junction to ambient ^(b)	$R_{\Theta JA}$	155	°C/W

NOTES:

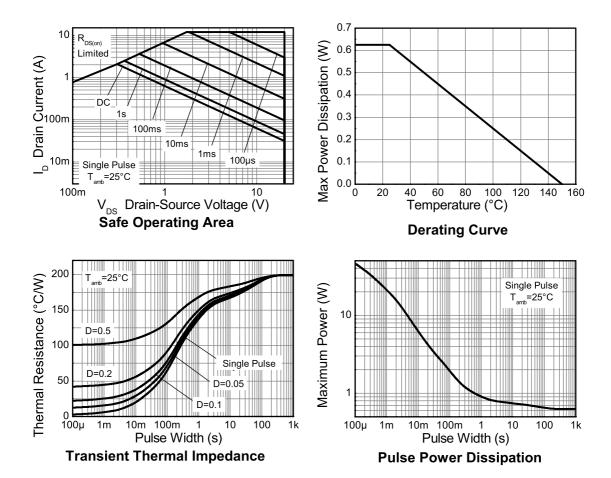
⁽a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions

⁽b) For a device surface mounted on FR4 PCB measured at t $\leq\!5$ sec.

⁽c) Repetitive rating - 25mm x 25mm FR4 PCB, D=0.02, pulse width $300\mu s$ - pulse width limited by maximum junction temperature.

ZXMN2B01F

Thermal characteristics



Electrical characteristics (at T_{amb} = 25°C unless otherwise stated)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static	•	•	•			
Drain-source breakdown voltage	V _{(BR)DSS}	20			V	$I_D = 250 \mu A, V_{GS} = 0 V$
Zero gate voltage drain current	I _{DSS}			1	μΑ	V _{DS} = 20V, V _{GS} =0V
Gate-body leakage	I _{GSS}			100	nA	V _{GS} =±8V, V _{DS} =0V
Gate-source threshold voltage	V _{GS(th)}	0.4		1.0	V	$I_D = 250 \mu A$, $V_{DS} = V_{GS}$
Static drain-source on-state	R _{DS(on)}			0.100	Ω	V _{GS} = 4.5V, I _D = 2.4A
resistance ^(*)				0.150	Ω	$V_{GS} = 2.5V, I_{D} = 2.0A$
				0.200	Ω	V _{GS} = 1.8V, I _D = 1.7A
Forward transconductance(*)(‡)	g _{fs}		6.1		S	V _{DS} = 10V, I _D = 2.4A
Dynamic ^(‡)	l		l			1
Input capacitance	C _{iss}		370		pF	V _{DS} = 10V, V _{GS} =0V
Output capacitance	C _{oss}		81		pF	f=1MHz
Reverse transfer capacitance	C _{rss}		46		pF	
Switching (†) (‡)	l		l			1
Turn-on-delay time	t _{d(on)}		2.2		ns	V _{DD} = 10V, V _{GS} = 4.5V
Rise time	t _r		3.6		ns	I _D = 1A
Turn-off delay time	t _{d(off)}		17.8		ns	$R_{G} \approx 6.0\Omega$
Fall time	t _f		10.5		ns	
Total gate charge	Q_g		4.8		nC	V _{DS} = 10V, V _{GS} = 4.5V
Gate-source charge	Q_{gs}		0.6		nC	I _D = 2.4A
Gate drain charge	Q_{gd}		1.0		nC	
Source-drain diode	l		l			1
Diode forward voltage ^(*)	V _{SD}		0.73	0.95	V	T _j =25°C, I _S = 1.2A, V _{GS} =0V
Reverse recovery time ^(‡)	t _{rr}		6.7		ns	T _j =25°C, I _F = 1.1A,
Reverse recovery charge ^(‡)	Q _{rr}		1.3		nC	di/dt=100A/ms

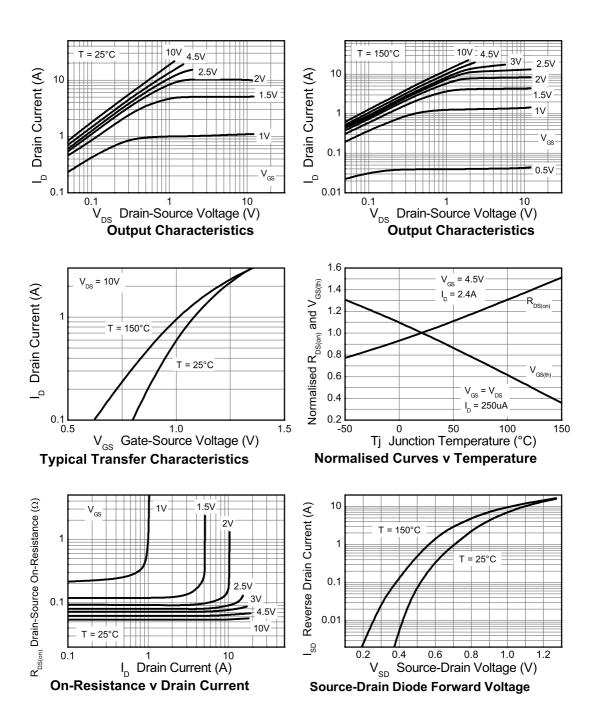
NOTES:

^(*) Measured under pulsed conditions. Pulse width ${\leq}300\mu\text{s};$ duty cycle ${\leq}2\%.$

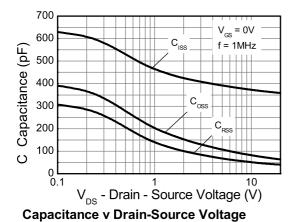
^(†) Switching characteristics are independent of operating junction temperature.

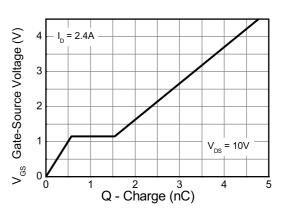
 $^{(\}ddagger)$ For design aid only, not subject to production testing.

Typical characteristics

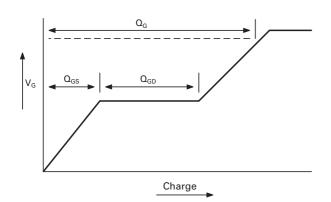


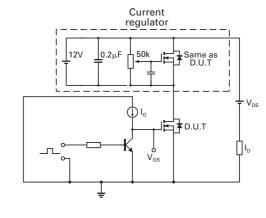
Typical characteristics





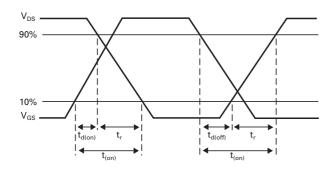
Gate-Source Voltage v Gate Charge

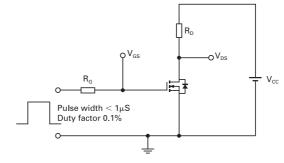




Basic gate charge waveform

Gate charge test circuit



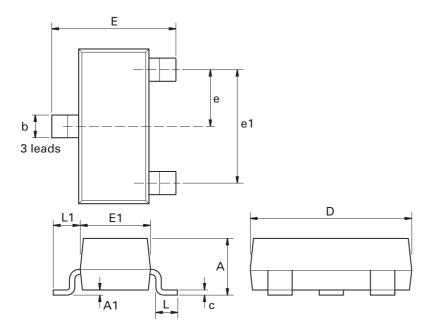


Switching time waveforms

Switching time test circuit

ZXMN2B01F

Package outline - SOT23



Dim.	Millin	neters	Inc	hes	Dim.	Millimeters		Inches	
	Min.	Max.	Min.	Max.		Min.	Max.	Max.	Max.
Α	-	1.12	-	0.044	e1	1.90	NOM	0.075	NOM
A1	0.01	0.10	0.0004	0.004	Е	2.10	2.64	0.083	0.104
b	0.30	0.50	0.012	0.020	E1	1.20	1.40	0.047	0.055
С	0.085	0.120	0.003	0.008	L	0.25	0.62	0.018	0.024
D	2.80	3.04	0.110	0.120	L1	0.45	0.62	0.018	0.024
е	0.95	NOM	0.0375	NOM	-	-	-	-	-

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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